

World Metrology Day 2019 in P.R. China

Invited by the State Administration for Market Regulation, China's competent metrological authority, Mr. Anthony Donnellan, Director of the International Bureau of Legal Metrology, attended the ceremony in celebration of this year's World Metrology Day, for which the theme is "The International System of Units - Fundamentally Better".

On May 20, nearly 500 Chinese and overseas guests, academicians, experts and scholars from the metrology field gathered at the China Hall of Science and Technology in Beijing and participated in the event. At the gathering, Qin Yizhi, Deputy Director (minister level) of the State Administration for Market Regulation announced that China would officially implement the new definitions of the SI base units from May 20th, and pointed out that metrology is an important foundation for the development of integrated national strategies and strategic capabilities while the International System of Units is the cornerstone of the global measurement system.

The quantization reform of metrology has made extreme measurement a possibility and enabled reproduction of measurement benchmarks, irrespective of time and place. As a result, the most accurate benchmarks can be directly applied to people's production and life. The State Administration for Market Regulation will abide by the resolutions of the General Conference of Weights and Measures, continue to implement the national legal measurement units based on the SI, and take this opportunity presented by the resolution on the redefinition of the base units of the SI to establish and perfect a dynamic metrological system and speed up the quantization of metrology in China.

All these efforts aim to add value and weight to metrology, which plays the role of a ballast in the ship named 'quality development'. During his speech at the event, Mr. Donnellan thanked China for the active role it plays in international metrological affairs.

Later on the same day, Mr. Donnellan headed to Shanghai to attend the 2019 China (Shanghai) International Metrology and Testing Technology and Equipment Exhibition, hosted by the Shanghai Metrology Association under the supervision of the Shanghai Market Supervision Administration.

As the metrological administrative department of Shanghai, which is China's famous center of economy, international financial and trade, international shipping and science and technology innovation, the Shanghai Market Supervision Administration is strengthening the management of legal metrology, optimizing metrological services, and improving measurement technology in order to give full play to metrology as a quality infrastructure.

At the exhibition, Mr. Donnellan delivered a special report entitled "OIML Certificate Mutual Recognition System and International Coordination". The exhibition attracted 13,000 metrological practitioners from various metrological administrative departments, technical institutions, industrial academies/associations, universities, scientific research institutions, and manufacturers from all over China.

On May 23, Mr. Donnellan was invited to the Shanghai Institute of Metrology and Testing Technology to attend the Shanghai Academic Forum on Time and Frequency themed "A New Era Ushered in by Quantization" and delivered a special report entitled "OIML Overview and the Development of Legal Metrology". He also witnessed the unveiling of the Shanghai Laboratory of National Time and Frequency Measurement Center and the signing of applications, and took a tour around relevant laboratories.

As a result of Mr. Donnellan's trip to China, a sound connection was established between the OIML and Chinese metrological practitioners, enabling participants at various levels to obtain a concrete understanding of the OIML and the OIML-CS and lending precious experience and inspiration to the further internationalization of China's metrological affairs.